

09548826\_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09548826 on February 20, 2004

7	714/718	(4 OR, 3 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/718	.Memory testing
6	324/755	(1 OR, 5 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
	324/537	.Of individual circuit component or element
	324/754	..With probe elements
	324/755	...Internal of or on support for device under test (DUT)
6	324/765	(3 OR, 3 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
	324/537	.Of individual circuit component or element
	324/765	..Test of semiconductor device
6	365/201	(4 OR, 2 XR)
	Class 365 :	STATIC INFORMATION STORAGE AND RETRIEVAL
	365/189.01	READ/WRITE CIRCUIT
	365/201	.Testing
4	257/203	(1 OR, 3 XR)
	Class 257 :	ACTIVE SOLID-STATE DEVICES
	257/202	GATE ARRAYS
	257/203	.With particular chip input/output means
4	257/48	(3 OR, 1 XR)
	Class 257 :	ACTIVE SOLID-STATE DEVICES
	257/48	TEST OR CALIBRATION STRUCTURE
4	257/723	(0 OR, 4 XR)
	Class 257 :	ACTIVE SOLID-STATE DEVICES
	257/688	.With large area flexible electrodes in press contact with opposite sides of active semiconductor chip and surrounded by an insulating element, e.g., ring

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257/723 .For plural devices

4 365/233 (0 OR, 4 XR)  
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
 365/230.01 ADDRESSING  
 365/233 .Sync/clocking

3 257/E21.525 (0 OR, 3 XR)  
 Class 257 : ACTIVE SOLID-STATE DEVICES  
 257/E21.515 .....Involving use of mechanical auxiliary part  
 without use of alloying or soldering process, e.g.,  
 pressure contacts (EPO)  
 257/E21.521 .Testing or measuring during manufacture or  
 treatment or reliability measurement, i.e.  
 , testing of  
 parts followed by no processing which modifies parts as  
 such (EPO)  
 257/E21.525 ..Procedures, i.e., sequence of activities  
 consisting of plurality of measurement and  
 correction,  
 marking or sorting steps (EPO)

3 257/E23.171 (0 OR, 3 XR)  
 Class 257 : ACTIVE SOLID-STATE DEVICES  
 257/E23.139 ...Liquid at normal operating temperature of  
 device (EPO)  
 257/E23.141 .Arrangements for conducting electric current  
 within device in operation from one component to another,  
 interconnections, e.g., wires, lead frames (EPO)  
 257/E23.169 ..Interconnection structure between plurality  
 of semiconductor chips being formed on or  
 in insulating  
 substrates (EPO)  
 257/E23.171 ...Adaptable interconnections, e.g., for  
 engineering changes (EPO)

3 257/E25.023 (0 OR, 3 XR)  
 Class 257 : ACTIVE SOLID-STATE DEVICES  
 257/E25.001 ASSEMBLIES CONSISTING OF PLURALITY OF  
 INDIVIDUAL SEMICONDUCTOR OR OTHER SOLID-STATE DEVICES  
 (EPO)

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257/E25.002 .All devices being of same type, e.g.,  
assemblies of rectifier diodes (EPO)  
257/E25.022 ..Devices having separate containers (EPO)  
257/E25.023 ...Device consisting of plurality of  
semiconductor or other solid-state devices  
or components  
formed in or on common substrate, e.g., int  
egrated circuit  
device (EPO)

3 324/158.1 (0 OR, 3 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/158.1 MISCELLANEOUS

3 333/247 (3 OR, 0 XR)

Class 333 : WAVE TRANSMISSION LINES AND NETWORKS  
333/245 LONG LINE ELEMENTS AND COMPONENTS  
333/246 .Strip type  
333/247 ..Semiconductor mounts

3 365/200 (2 OR, 1 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL  
365/189.01 READ/WRITE CIRCUIT  
365/200 .Bad bit

3 438/15 (2 OR, 1 XR)

Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS  
  
438/14 WITH MEASURING OR TESTING  
438/15 .Packaging (e.g., with mounting, encapsulating  
etc.) or treatment of packaged semiconducto

3 714/724 (1 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing

2 257/678 (0 OR, 2 XR)

Class 257 : ACTIVE SOLID-STATE DEVICES  
257/678 HOUSING OR PACKAGE

2 257/730 (0 OR, 2 XR)

Class 257 : ACTIVE SOLID-STATE DEVICES  
257/688 .With large area flexible electrodes in press  
contact with opposite sides of active semi

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conductor chip

and surrounded by an insulating element, e

.g., ring

257/730

.Outside periphery of package having specified shape or configuration

2 257/777 (0 OR, 2 XR)

Class 257 : ACTIVE SOLID-STATE DEVICES

257/734 COMBINED WITH ELECTRICAL CONTACT OR LEAD

257/777 .Chip mounted on chip

2 257/778 (1 OR, 1 XR)

Class 257 : ACTIVE SOLID-STATE DEVICES

257/734 COMBINED WITH ELECTRICAL CONTACT OR LEAD

257/778 .Flip chip

2 257/E21.512 (0 OR, 2 XR)

Class 257 : ACTIVE SOLID-STATE DEVICES

257/E21.001 PROCESSES OR APPARATUS ADAPTED FOR MANUFACTURE

OR TREATMENT OF SEMICONDUCTOR OR SOL

ID-STATE DEVICES

OR OF

PARTS THEREOF (EPO)

257/E21.002 .Manufacture or treatment of semiconductor device (EPO)

257/E21.04 ..Device having at least one potential-jump barrier or surface barrier, e.g., PN j

unction,  
depletion

layer, carrier concentration layer (EP

O)

257/E21.499 ...Assembling semiconductor devices, e.g., packaging , including mounting, encapsu

lating, or  
treatment

of packaged semiconductor (EPO)

257/E21.506 ....Attaching or detaching leads or other conductive members, to be used for carry

ing current to  
or

from device in operation (EPO)

257/E21.509 .....Involving soldering or alloying process, e.g., soldering wires (EPO)

257/E21.511 .....Mounting on insulating member provided with metallic leads, e.g., flip-chip mount

ing, conductive

die mounting (EPO)

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257/E21.512 .....Right-up bonding (EPO)

2 257/E23.004 (0 OR, 2 XR)  
 Class 257 : ACTIVE SOLID-STATE DEVICES  
 257/E23.001 PACKAGING, INTERCONNECTS, AND MARKINGS FOR  
 SEMICONDUCTOR OR OTHER SOLID-STATE DEVICE  
 S (EPO)

257/E23.003 .Mountings, e.g., nondetachable insulating  
 substrates (EPO)

257/E23.004 ..Characterized by shape (EPO)

2 257/E23.069 (0 OR, 2 XR)  
 Class 257 : ACTIVE SOLID-STATE DEVICES  
 257/E23.001 PACKAGING, INTERCONNECTS, AND MARKINGS FOR  
 SEMICONDUCTOR OR OTHER SOLID-STATE DEV  
 ICES (EPO)

257/E23.01 .Arrangements for conducting electric current  
 to or from solid-state body in operatio  
 n, e.g., leads,  
 terminal arrangements (EPO)

257/E23.023 ..Consisting of soldered or bonded  
 constructions (EPO)

257/E23.06 ...Leads, i.e., metallizations or lead frames  
 on insulating substrates, e.g., chip carr  
 iers (EPO)

257/E23.068 ....Additional leads joined to metallizations  
 on insulating substrate, e.g., pins, bumps  
 , wires, flat  
 leads (EPO)

257/E23.069 .....Spherical bumps on substrate for external  
 connection, e.g., ball grid arrays (BGA) (E  
 PO)

2 257/E23.07 (0 OR, 2 XR)  
 Class 257 : ACTIVE SOLID-STATE DEVICES  
 257/E23.001 PACKAGING, INTERCONNECTS, AND MARKINGS FOR  
 SEMICONDUCTOR OR OTHER SOLID-STATE DEVI  
 CES (EPO)

257/E23.01 .Arrangements for conducting electric current  
 to or from solid-state body in operation  
 , e.g., leads,  
 terminal arrangements (EPO)

257/E23.023 ..Consisting of soldered or bonded  
 constructions (EPO)

257/E23.06 ...Leads, i.e., metallizations or lead frames  
 on insulating substrates, e.g., chip carri  
 ers (EPO)

257/E23.07 ....Geometry or layout (EPO)

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- 2 324/754 (0 OR, 2 XR)
  - Class 324 : ELECTRICITY: MEASURING AND TESTING
  - 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
  - 324/537 .Of individual circuit component or element
  - 324/754 ..With probe elements
- 2 324/758 (0 OR, 2 XR)
  - Class 324 : ELECTRICITY: MEASURING AND TESTING
  - 324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
  - 324/537 .Of individual circuit component or element
  - 324/754 ..With probe elements
  - 324/758 ...Probe alignment or positioning
- 2 333/33 (0 OR, 2 XR)
  - Class 333 : WAVE TRANSMISSION LINES AND NETWORKS
  - 333/24R COUPLING NETWORKS
  - 333/32 .With impedance matching
  - 333/33 ..Having long line elements
- 2 361/684 (0 OR, 2 XR)
  - Class 361 : ELECTRICITY: ELECTRICAL SYSTEMS AND DEVICES
  - 361/600 HOUSING OR MOUNTING ASSEMBLIES WITH DIVERSE ELECTRICAL COMPONENTS
  - 361/679 .For electronic systems and devices
  - 361/683 ..Computer related support
  - 361/684 ...Memory unit support
- 2 361/783 (0 OR, 2 XR)
  - Class 361 : ELECTRICITY: ELECTRICAL SYSTEMS AND DEVICES
  - 361/600 HOUSING OR MOUNTING ASSEMBLIES WITH DIVERSE ELECTRICAL COMPONENTS
  - 361/679 .For electronic systems and devices
  - 361/748 ..Printed circuit board
  - 361/760 ...Connection of components to board
  - 361/783 ....Having semiconductive device
- 2 365/230.03 (0 OR, 2 XR)
  - Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
  - 365/230.01 ADDRESSING
  - 365/230.03 .Plural blocks or banks
- 2 713/2 (2 OR, 0 XR)
  - Class 713 : ELECTRICAL COMPUTERS AND DIGITAL PROCESSING

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SYSTEMS: SUPPORT

713/1 DIGITAL DATA PROCESSING SYSTEM INITIALIZATION  
OR CONFIGURATION (E.G., INITIALIZING, SET  
UP,  
CONFIGURATION, OR RESETTING)

713/2 .Loading initialization program (e.g., booting  
, rebooting, warm booting, remote booting, BI  
OS, initial program load (IPL), bootstrapping)

2 714/25 (0 OR, 2 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
714/1 .Reliability and availability  
714/25 ..Fault locating (i.e., diagnosis or testing)

2 714/44 (1 OR, 1 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
714/1 .Reliability and availability  
714/25 ..Fault locating (i.e., diagnosis or testing)  
714/40 ...Component dependent technique  
714/44 ....Peripheral device component fault

2 714/46 (1 OR, 1 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING  
714/1 .Reliability and availability  
714/25 ..Fault locating (i.e., diagnosis or testing)  
714/46 ...Operator interface for diagnosing or testin  
g

2 714/47 (0 OR, 2 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

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714/1 .Reliability and availability  
714/47 ..Performance monitoring for fault avoidance

- 2 714/732 (1 OR, 1 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/732 ..Signature analysis
- 2 714/733 (1 OR, 1 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/733 ..Built-in testing circuit (BILBO)



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PLUS Search Results for S/N 09548826, Searched February 20, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

6076177  
4992849  
4992850  
RE36325  
5266912  
5400003  
5612657  
6249052  
6002178  
5241266  
5424652  
5457400  
5483174  
5483175  
5807762  
5825195  
5959310  
6087676  
5450576  
5659748  
4499581  
5796746  
5812472  
5912852  
5914902  
5995424  
6182253  
5862146  
6304499  
5798961  
5423050  
5745501  
5953690  
6691055  
5875136  
6119049  
4414669

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4841434  
5805606  
5249450  
5336649  
5342807  
5359547  
5652754  
5727000  
5808919  
5954827  
6049896  
6133745  
6415397

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Most Frequently Occurring Classifications of Patents Returned  
From A Search of 09548826 on February 20, 2004

Original Classifications

4 365/201  
4 714/718  
3 257/48  
3 324/765  
3 333/247  
2 365/200  
2 438/15  
2 713/2

Cross-Reference Classifications

5 324/755  
4 257/723  
4 365/233  
3 257/203  
3 257/E21.525  
3 257/E23.171  
3 257/E25.023  
3 324/158.1  
3 324/765  
3 714/718  
2 257/678  
2 257/730  
2 257/777  
2 257/E21.512  
2 257/E23.004  
2 257/E23.069  
2 257/E23.07  
2 324/754  
2 324/758  
2 333/33  
2 361/684  
2 361/783  
2 365/201  
2 365/230.03  
2 714/25  
2 714/47  
2 714/724

Combined Classifications

7 714/718  
6 324/755  
6 324/765  
6 365/201

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4 257/203  
4 257/48  
4 257/723  
4 365/233  
3 257/E21.525  
3 257/E23.171  
3 257/E25.023  
3 324/158.1  
3 333/247  
3 365/200  
3 438/15  
3 714/724  
2 257/678  
2 257/730  
2 257/777  
2 257/778  
2 257/E21.512  
2 257/E23.004  
2 257/E23.069  
2 257/E23.07  
2 324/754  
2 324/758  
2 333/33  
2 361/684  
2 361/783  
2 365/230.03  
2 713/2  
2 714/25  
2 714/44  
2 714/46  
2 714/47  
2 714/732  
2 714/733